In this paper, X-ray diffraction behavior of a big [011] oriented grain (millimeter scale) which deviated from the sample surface by 10.6 degree in oriented 3% silicon steel was studied. The results showed that diffraction from the (011) crystal planes was very strong, if normal of the (011) planes was just on diffraction plane. However, the diffraction intensity of the grain decreased other than vanished, if the normal of the crystal planes deviated from diffraction plane through rotating the sample was around its surface normal. Nevertheless, it was found that the bigger of the deviating angle between the normal of the crystal planes and diffraction plane, the lower of the diffraction intensity from (011) crystal planes of the grain. The diffraction intensity decreased to 53.6 percent and 36.8 percent of the strongest intensity, if the sample was rotated by 10 degree and 15 degree around its surface normal from the position in which the normal of (011) crystal planes was just on the diffraction plane.
I permit to post my abstract on the DXC web site and affiliated web sites.

Sperker’s information
Name: Jianfeng Fang
Mailing address: Central Iron and Steel Research Institute, Powder Metallurgy
Department, Xueyuan Nanlu No.76, Haidian distract, Beijing, 100081, P.R. China
Phone number: 86-010-62182821
Fax number: 86-010-62182821
E-mail address: jf.fang@263.net, jf-fang@hotmail.com

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